

<b>Notice of References Cited</b>	Application/Control No. 10/583,201	Applicant(s)/Patent Under Reexamination HAUG, KARSTEN	
	Examiner David S. Baker	Art Unit 2884	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,704,375 A	11-1972	Slawek et al.	257/443
	B	US-			
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	D	US-			
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	K	US-			
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	M	US-			

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	P	FR 2732849 A1	10-1996	France	ALBOU et al.	
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NON-PATENT DOCUMENTS

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	U	
	V	
	W	
	X	

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